# Calcium sulfide powder analyzed by XPS

Cite as: Surf. Sci. Spectra 30, 014005 (2023); https://doi.org/10.1116/6.0002304 Submitted: 20 October 2022 • Accepted: 11 January 2023 • Published Online: 10 February 2023



# **ARTICLES YOU MAY BE INTERESTED IN**

Lanthanum sulfide powder analyzed by XPS Surface Science Spectra 30, 014001 (2023); https://doi.org/10.1116/6.0002252

1,3-Dimethyl-imidazolium dimethyl phosphate ([MMIM]<sup>+</sup>[DMP]<sup>-</sup>) analyzed by XPS and HAXPES

Surface Science Spectra 30, 014006 (2023); https://doi.org/10.1116/6.0002297

Surface Y<sub>2</sub>O<sub>3</sub> layer formed on air exposed Y powder characterized by XPS Surface Science Spectra 27, 024010 (2020); https://doi.org/10.1116/6.0000475



• end point detection in ion beam etch

elemental imaging - surface mapping

kinetic studies

SIMS

 partial pressure mea of process gases + etch and deposition process reaction reactive sputter process control analysis of neutral and radical species vacuum diagnostics vacuum coating process monitoring

Surf. Sci. Spectra 30, 014005 (2023); https://doi.org/10.1116/6.0002304 © 2023 Author(s).

catalysis and thermal analysis

dissolved species probes
fermentation, environmental and ecological studies

molecular beam studies

www.HidenAnalytical.com

Info@hideninc.com





# Calcium sulfide powder analyzed by XPS

Cite as: Surface Science Spectra **30**, 014005 (2023); doi: 10.1116/6.0002304 Submitted: 20 October 2022 · Accepted: 11 January 2023 · Published Online: 10 February 2023



Brian Butkus,<sup>1</sup> D Matthew Havel,<sup>1,2</sup> Alexandros Kostogiannes,<sup>1,2</sup> Andrew Howe,<sup>2</sup> Myungkoo Kang,<sup>2</sup> Romain Gaume,<sup>2,3</sup> Kathleen A. Richardson,<sup>1,2</sup> B and Parag Banerjee<sup>1,3,4,5</sup>

# AFFILIATIONS

<sup>1</sup>Department of Materials Science and Engineering, University of Central Florida, Orlando, Florida 32816

<sup>2</sup>College of Optics and Photonics, University of Central Florida, Florida 32816

<sup>3</sup>NanoScience Technology Center, University of Central Florida, Florida 32816

<sup>4</sup>Florida Solar Energy Center, University of Central Florida, Florida 32816

<sup>5</sup>REACT Faculty Cluster, University of Central Florida, Florida 32816

# ABSTRACT

X-ray photoelectron spectroscopy was performed on as-received, calcium sulfide (CaS) powder (98.0%), doped with europium (Eu) 2.0 wt. %. The scans provide photoelectron spectroscopy investigation data for CaS to help with identification of sulfide compounds. This report includes charge corrected scans for the survey along with S 2s, S 2p, O 1s, Eu 3d, Ca 2s, Ca 2p, and C 1s surface photoelectron signals.

Key words: CaS, sulfides, phosphor, x-ray photoelectron spectroscopy, XPS

Published under an exclusive license by the AVS. https://doi.org/10.1116/6.0002304

Accession #: 01818	Major Elements in Spectra: Ca, S
Technique: XPS	Minor Elements in Spectra: O, C, Eu
Host Material: CaS, powder doped with Eu	Published Spectra: 8
Instrument: XPS ESCALAB 250Xi Fisher Scientific	Spectral Category: Comparison

### INTRODUCTION

Calcium sulfide (CaS) has historically been used as a phosphor. CaS doped with europium (Eu) is a common red phosphor with an emission at 645 nm (Ref. 1). Along with the enhanced color emission, the doping increases the thermal stability of the material. Other historical uses include the production of pharmaceutical sulfur-based drugs. But new interest has broadened the uses and research in electronics, optical glasses, and ceramics, along with use in catalysis (Ref. 2). Examples of applications in each of the areas include nanocrystal for light-emitting diode production, broadband glasses, and ceramic application (i.e., UV and IR glass and ceramics) (Refs. 1-3). Catalysis research includes using CaS for the removal of heavy metals from groundwater (Ref. 4) and the conversion of drywall (gypsum board) to sulfur (Ref. 5) While there are some reports that include x-ray photoelectron spectroscopy (XPS) of CaS (Refs. 6 and 7), the data included in the reports are not complete, i.e., missing survey spectra data on collection and identification of peaks in fine spectra.

In this study, we analyze CaS doped with Eu by XPS to study and quantify the bonding states of Ca and S, along with minor species Eu, C, and O. Eu has been introduced at 2.0 wt. % during the synthesis of the compound. The peak fitting done in this report aims to identify bonding states of CaS. The use of XPS also provides quantification of atomic percentages (i.e., stoichiometry) along with the bonding states of additional constituent elements and non-trace level impurities, if present.

#### SPECIMEN DESCRIPTION (ACCESSION # 01818)

Host Material: Calcium sulfide CaS bulk powder

CAS Registry #: 20548-54-3

Host Material Characteristics: Homogeneous; powder; polycrystalline; semiconductor; inorganic compound; powder

Chemical Name: Calcium sulfide 98.0 wt. % doped with europium 2.0 wt. %

Source: Lorad Chemical Corporation, 1200 19th Street North, St. Petersburg, FL 33713, USA



Host Composition: CaS 98.0 wt. % and Eu 2.0 wt. %

Form: 98.0% purity powder CaS

Structure: Halite (cubic), cF8

**History and Significance:** The specimen was received in a vacuum sealed glass bottle and stored in an inert atmosphere chamber at room temperature. CaS is commonly used in Electronics, Optical glasses and ceramics, catalysts, pharmaceutical application.

As Received Condition: Light red powder

Analyzed Region: Same as host material

- *Ex Situ* **Preparation/Mounting:** Powder mounted on double-sided carbon tape.
- *In Situ* **Preparation:** Argon ion sputtering was used to clean the surface before analysis.
- **Charge Control:** Charge compensation is delivered by both an in-lens electrostatic electron flood source (1 eV,  $100 \,\mu$ A) and a dual-beam low energy electron and ion coaxial flood source (2 eV,  $100 \,\mu$ A).

Temp. During Analysis: 300 K

**Pressure During Analysis:**  $5 \times 10^{-8}$  Pa **Pre-analysis Beam Exposure:** 0 s

# INSTRUMENT DESCRIPTION

Manufacturer and Model: Thermo Fisher Scientific ESCALAB 250Xi Analyzer Type: Spherical sector Detector: Channeltron Number of Detector Elements: 6

# INSTRUMENT PARAMETERS COMMON TO ALL SPECTRA

# Spectrometer

- Analyzer Mode: constant pass energy
- **Throughput**  $(T = E^N)$ : Calculated from a polynomial fit to a plot of log [peak area/(PE × XSF)] versus log[KE/PE], where PE is the pass energy, KE is the kinetic energy, and XSF is the relative sensitivity factor.

Excitation Source Window: None Excitation Source: Al  $K_a$  monochromatic Source Energy: 1486.6 eV Source Strength: 200 W Source Beam Size: 200 × 200  $\mu$ m<sup>2</sup> Signal Mode: Single channel direct

## Geometry

Incident Angle: 58° Source-to-Analyzer Angle: 58° Emission Angle: 0° Specimen Azimuthal Angle: 90° Acceptance Angle from Analyzer Axis: 45° Analyzer Angular Acceptance Width: 22.5° × 22.5°

### Ion Gun

Manufacturer and Model: Thermo Fisher Scientific EX03 Ion Gun System

Energy: 3000 eV Current: 0.02 mA Current Measurement Method: Biased stage Sputtering Species:  $Ar^+$ Spot Size (unrastered):  $500 \,\mu$ m Raster Size:  $4500 \times 4500 \,\mu$ m<sup>2</sup> Incident Angle:  $40^{\circ}$ Polar Angle:  $40^{\circ}$ Azimuthal Angle:  $270^{\circ}$ 

**Comment:** These parameters correspond to ion cleaning methods used in typical operation requiring surface cleaning.

#### DATA ANALYSIS METHOD

**Energy Scale Correction:** Binding energy scale was referenced to C 1s = 284.8 eV.

- Recommended Energy Scale Shift: Shift +0.58 eV
- **Peak Shape and Background Method:** Thermo Scientific Avantage software version 5.9902 was used for peak fitting and background subtraction. The smart (Shirley function) was used to subtract the background for Ca 2s, Ca 2p, S 2p, S 2s, O 1s, C 1s, and Eu 3d peaks. Using the smart feature utilizes constraints that limit the background from having greater intensity than data from points in the collection region. After background subtraction, a mixed Gaussian (30%)-Lorentzian (70%) product function was used to fit the peaks after background subtraction.
- **Quantitation Method:** Atomic percentages were calculated using Thermo Scientific Avantage software version 5.9902. Sensitivity factors were obtained from the Thermo Scientific Avantage software database and used to calculate elemental atomic percentages. The peak library is ALWAG (Ref. 8).

#### ACKNOWLEDGMENTS

The authors thank the Lockheed Martin University Engagement and Applied Research organizations, the U.S. Naval Surface Warfare Center, the U.S. Army Research Laboratory, and the U.S. Air Force Research Laboratory for their integral and collaborative support of this research. The authors acknowledge the NSF MRI: ECCS: 1726636 and the MCF-AMPAC facility, MSE and CECS along with Kirk Scammon MCF Research Engineer and Lorad Chemical Corporation. This research was supported, in part, by the Florida High Tech Corridor's Matching Grant Research Program at the University of Central Florida.

#### AUTHOR DECLARATIONS

#### **Conflict of Interest**

The authors have no conflicts to disclose.



### Author Contributions

Brian Butkus: Conceptualization (equal); Data curation (equal); Formal analysis (equal); Investigation (equal); Methodology (equal); Software (equal); Validation (equal); Visualization (equal); Writing - original draft (equal). Matthew Havel: Investigation Methodology (supporting). (supporting); Alexandros Kostogiannes: Formal analysis (supporting); Investigation (supporting); Methodology (supporting); Writing - review & editing (supporting). Andrew Howe: Formal analysis (supporting); Investigation (supporting); Writing - review & editing (supporting). Myungkoo Kang: Conceptualization (supporting); Methodology (supporting); Writing - review & editing (supporting). Romain Gaume: Conceptualization (supporting); Formal analysis (supporting); Funding acquisition (equal); Resources (equal); Supervision (equal); Validation (supporting); Writing review & editing (supporting). Kathleen A. Richardson: Conceptualization (supporting); Data curation (supporting); Formal analysis (equal); Funding acquisition (lead); Investigation (supporting); Project administration (equal); Resources (equal); Supervision (equal); Writing - review & editing (supporting). Parag Banerjee: Conceptualization (equal); Data curation (equal);

Formal analysis (equal); Funding acquisition (equal); Investigation (equal); Methodology (equal); Project administration (lead); Resources (equal); Software (equal); Supervision (lead); Validation (equal); Visualization (equal); Writing – review & editing (equal).

# DATA AVAILABILITY

The data that support the findings of this study are available within the article and its supplementary material.

#### REFERENCES

 <sup>1</sup>N. Ruelle, M. Pham-Thi, and C. Fouassier, Jpn. J. Appl. Phys. 31, 2786 (1992).
<sup>2</sup>E. Shobhana, Optical Characterization of Calcium Sulphide (CaS) Thin Films by Chemical Bath Deposition, 2015.

<sup>3</sup>H. Nakamura, Y. Ogawa, A. Kasahara, and T. Kodama, J. Jpn. Inst. Met. **62**, 1137 (1998).

<sup>4</sup>C.-Y. Huang *et al.*, Water **13**, 2266 (2021).

- <sup>5</sup>M. de Beer *et al.*, Waste Manage. **34**, 2373 (2014).
- <sup>6</sup>S. Bahadur, D. Gong, and J. Anderegg, Wear **197**, 271 (1996).
- <sup>7</sup>R. Vercaemst et al., J. Lumin. 63, 19 (1995).
- <sup>8</sup>C. D. Wagner *et al.*, Surf. Interface Anal. 3, 211 (1981).

SPECTRAL FEATURES TABLE							
Spectrum ID #	Element/ Transition	Peak Energy (eV)	Peak Width FWHM (eV)	Peak Area (eV counts/s)	Sensitivity Factor	Concentration (at. %)	Peak Assignment
01818-02	S 2s	224.54	2.63	13 864.86	1.294		CaS
01818-03	S 2p <sub>3/2</sub>	160.78	2.45	21 373.11	1.881	32.7	CaS
01818-04	0 1s	530.89	2.81	15 477.98	2.881	16.96	Metal oxide/ carbonates
01818-05	Eu 3d <sub>5/2</sub>	1133.83	3.56	12 820.81	48.796	1.18	Eu
01818-06	Ca 2s	437.46	3.3	17 085.82	2.106		CaS, CaO,CaCO <sub>3</sub>
01818-07	Ca 2p <sub>3/2</sub>	345.78	1.52	57 501.87	5.97	28.86	CaS, CaO,CaCO <sub>3</sub>
01818-08	C 1s	284.64	2.22	6 873.88	1	20.3	C–C, C–H, carbonates

ANALYZER CALIBRATION TABLE							
Spectrum ID #	Element/ Transition	Peak Energy (eV)	Peak Width FWHM (eV)	Peak Area (eV counts/s)	Sensitivity Factor	Concentration (at. %)	Peak Assignment
	Au <i>4f</i>	84.05	0.57	262 830.05	20.735		Au
	Ag 3d	368.36	0.48	386 600.57	22.131		Ag
	Cu 2p	932.8	0.77	655 133.11	26.513	•••	Cu

GUIDE TO FIGURES						
Spectrum (Accession) #	Spectral Region	Voltage Shift <sup>a</sup>	Multiplier	Baseline	Comment #	
01818-01	Survey	-0.58	1	0	1	
01818-02	S 2s	-0.58	1	0	1	
01818-03	S 2p	-0.58	1	0	1	
01818-04	0 <i>1s</i>	-0.58	1	0	1	
01818-05	Eu <i>3d</i>	-0.58	1	0	1	
01818-06	Ca 2s	-0.58	1	0	1	
01818-07	Ca 2p	-0.58	1	0	1	
01818-08	C 1s	-0.58	1	0	1	

<sup>a</sup>Voltage shift of the archived (as-measured) spectrum relative to the printed figure. The figure reflects the recommended energy scale correction due to a calibration correction, sample charging, flood gun, or other phenomenon.

1. CaS powder.







Ka



Ka

AI

AI

Ka

Ka





